

Figure 2A

X-Ray Photoelectron Deffraction Graph
of a Si Substrate and SiGeC Layers with
Different C Concentrations

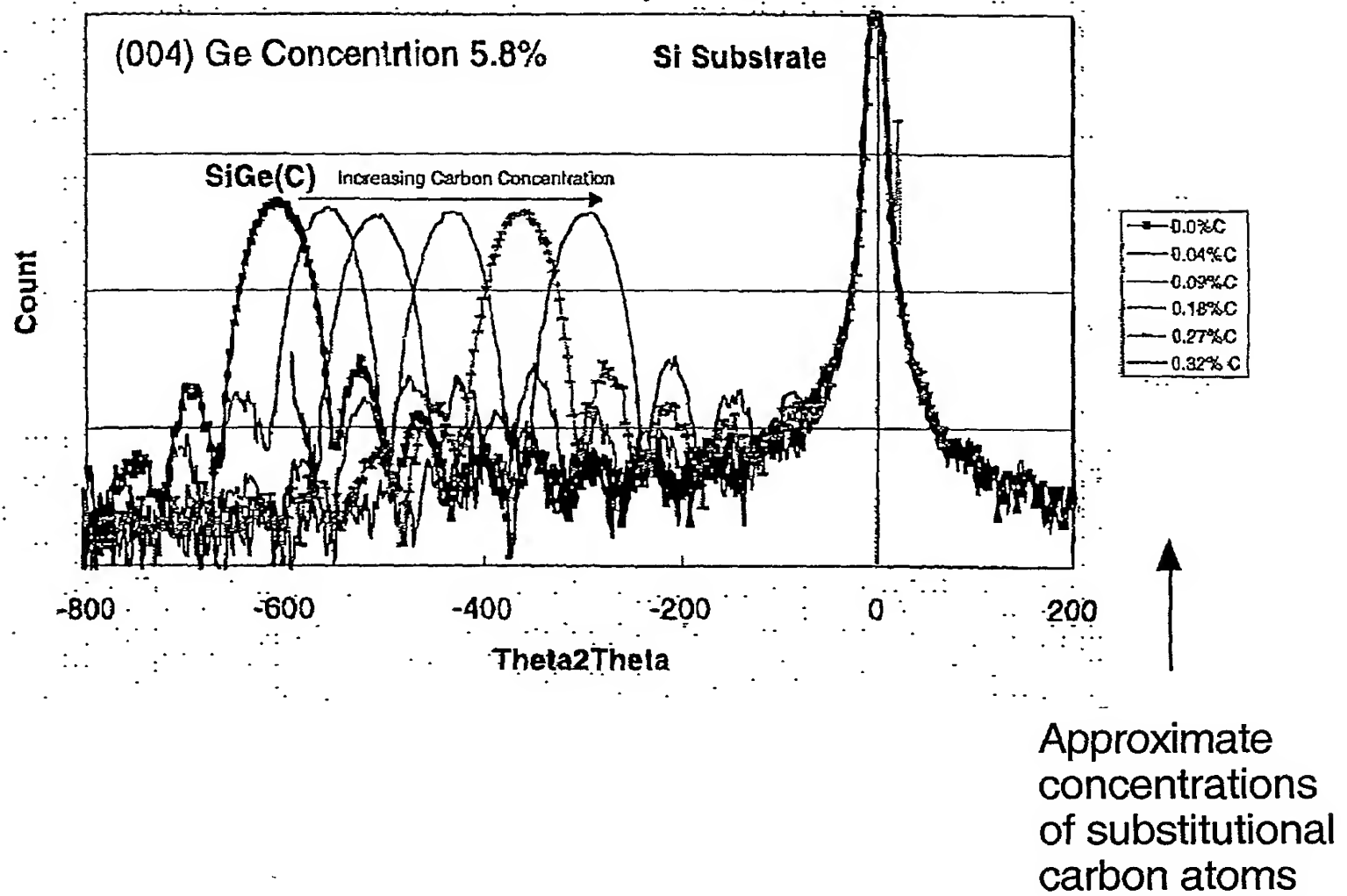


Figure 2B

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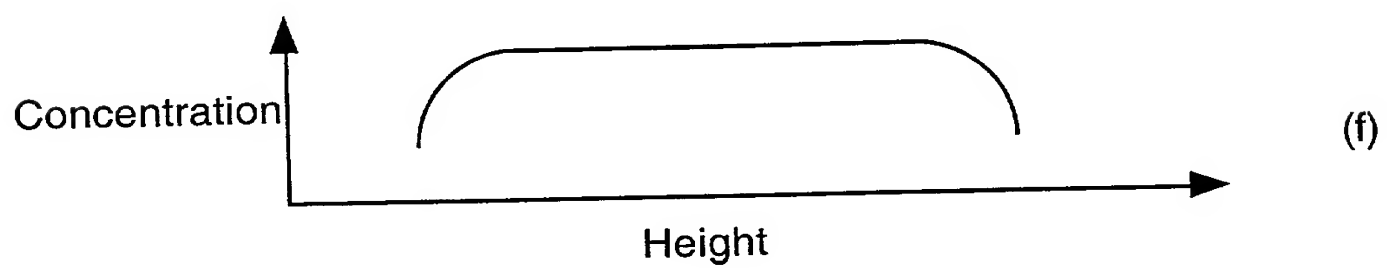
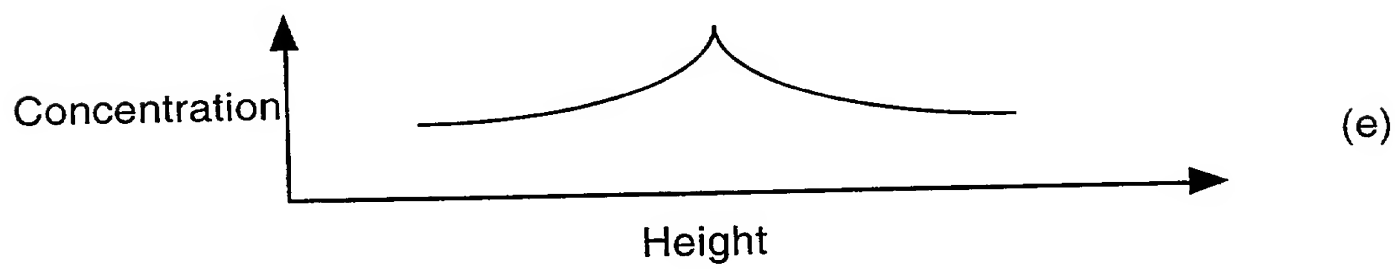
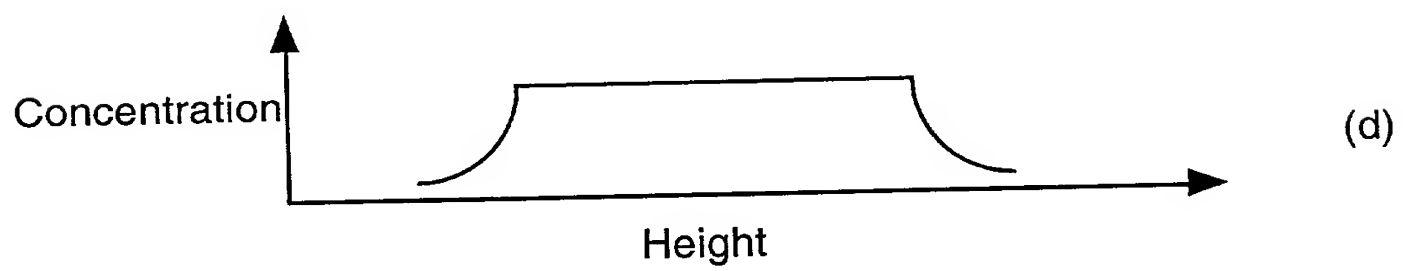
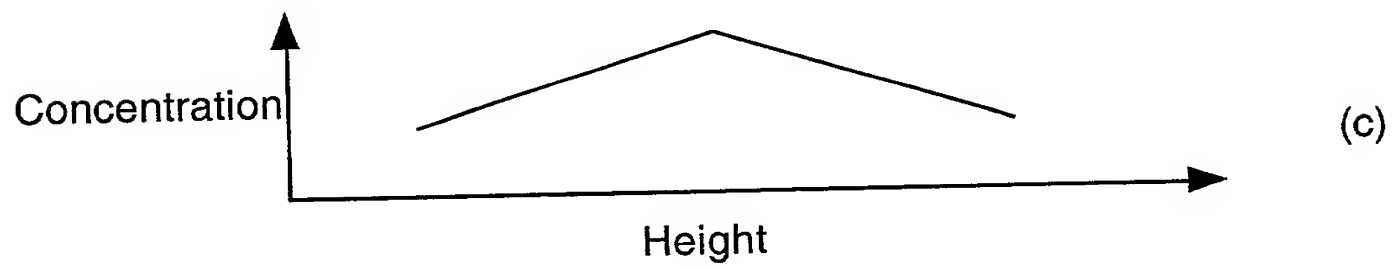
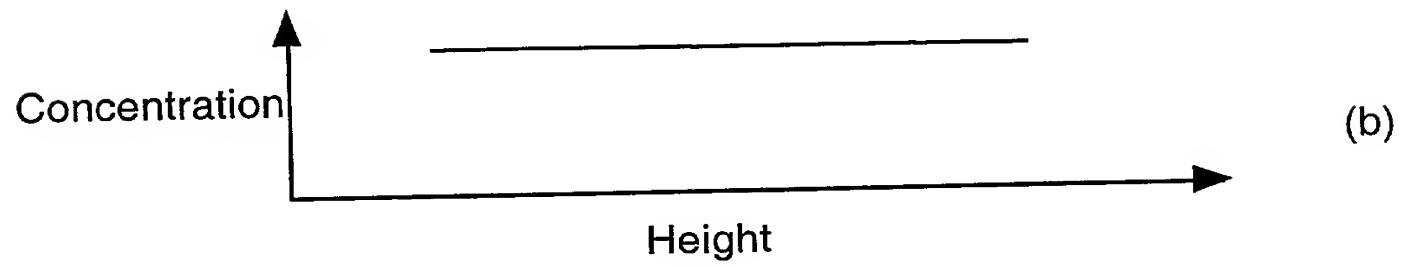
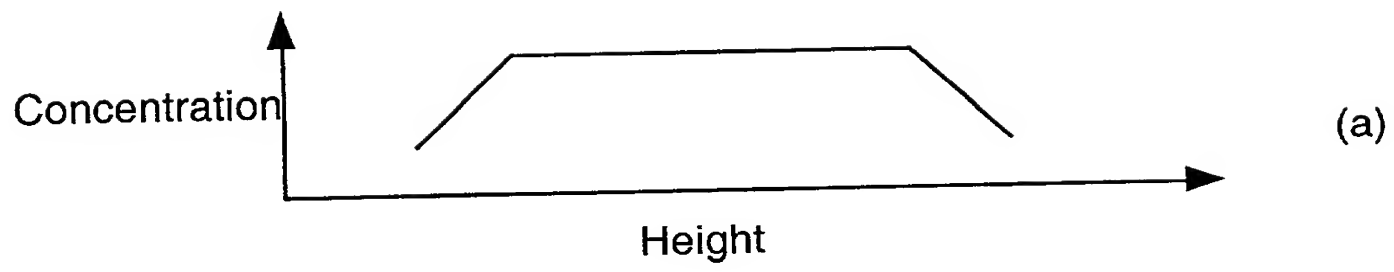


Figure 3

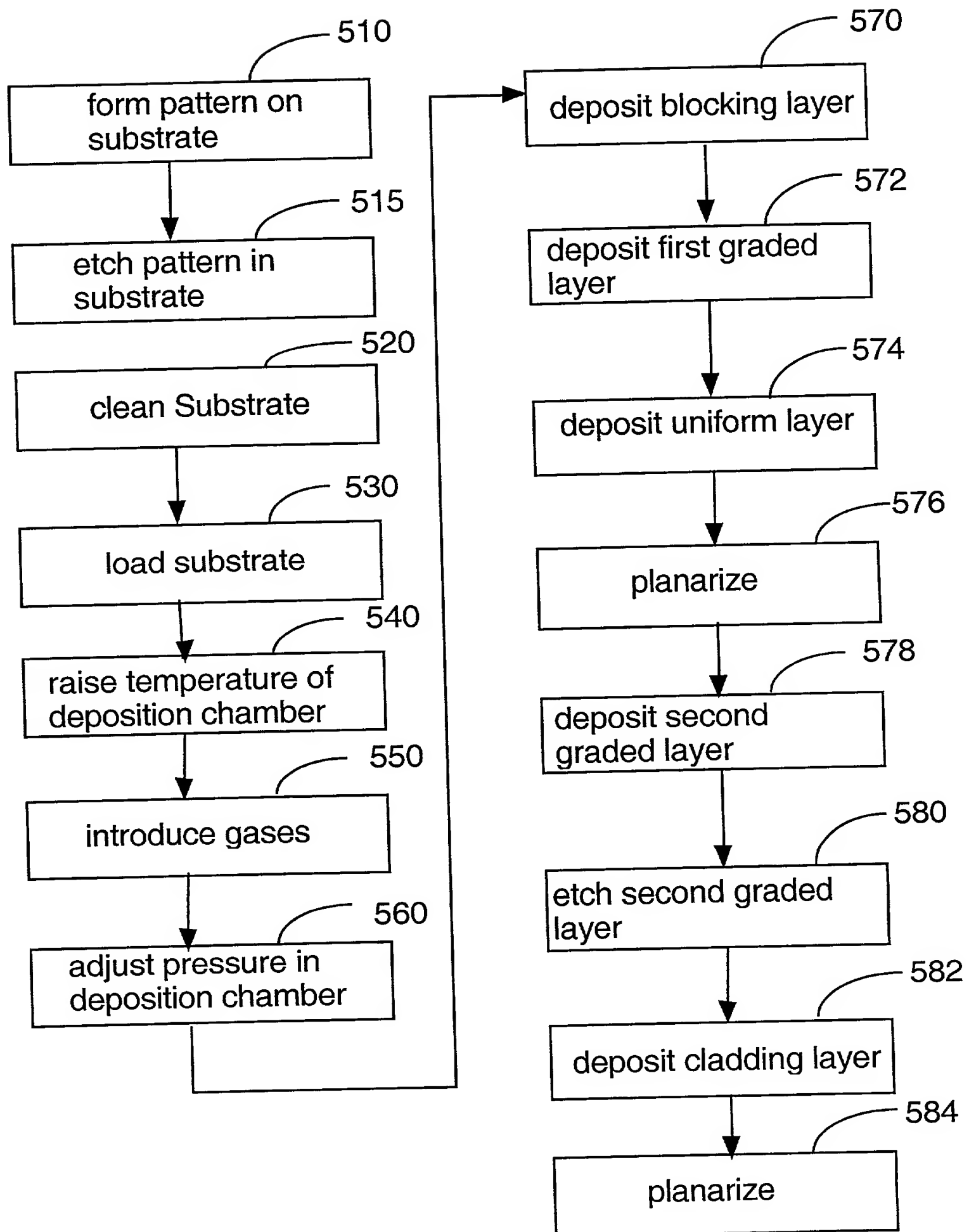
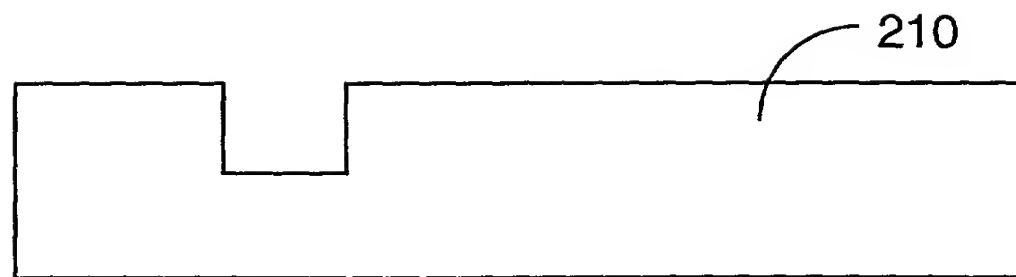
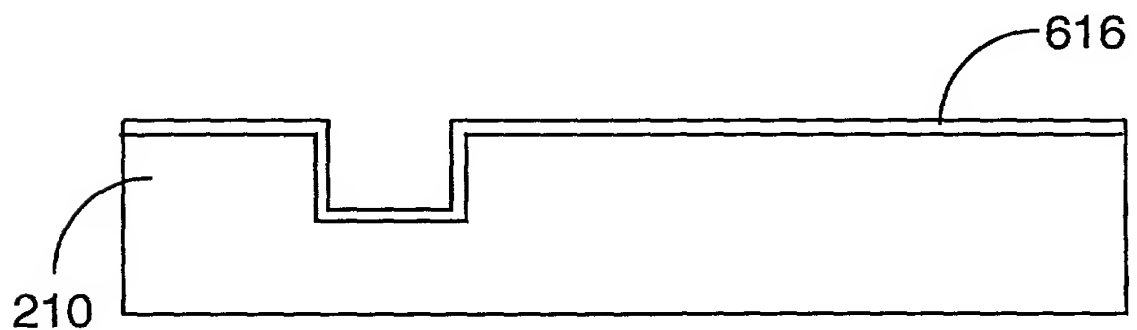


Figure 4

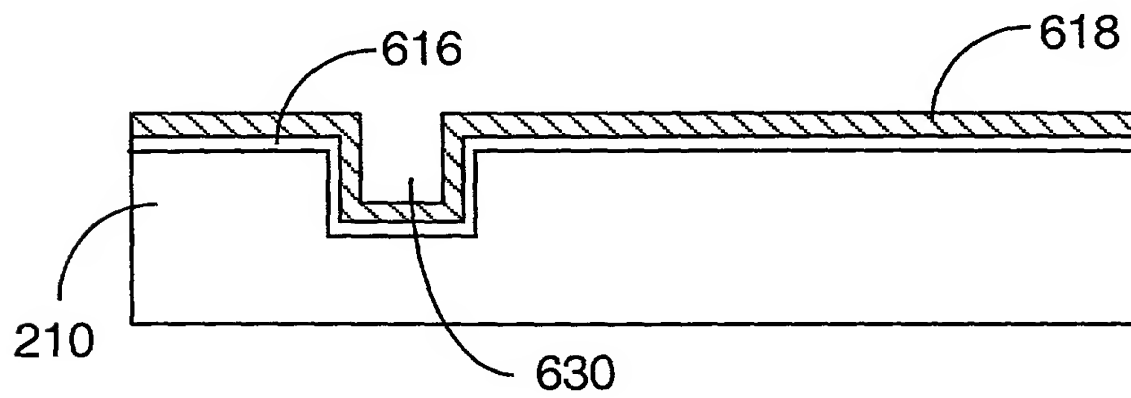
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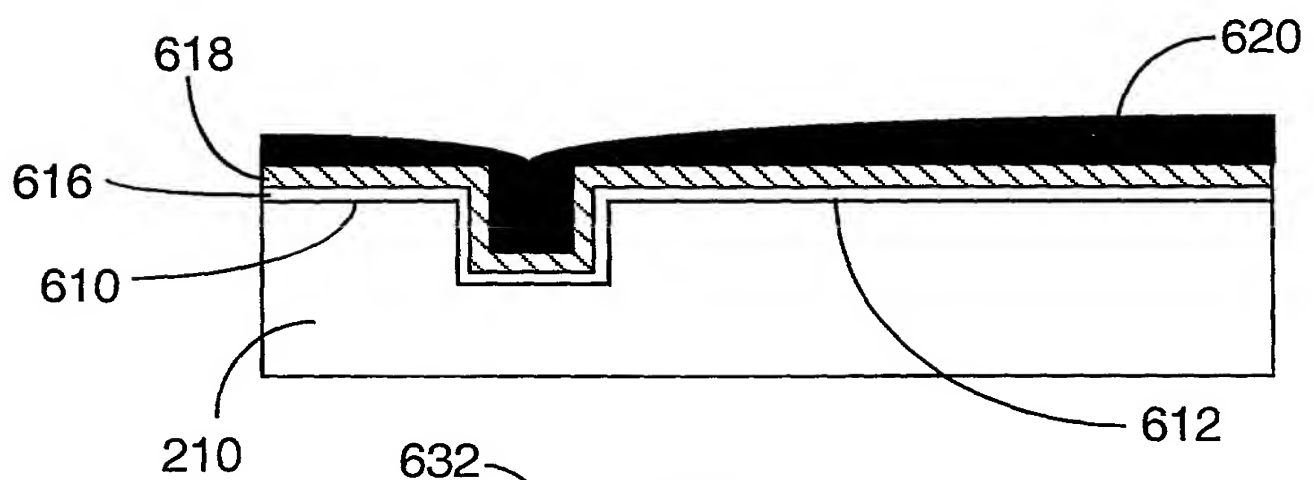
(a)



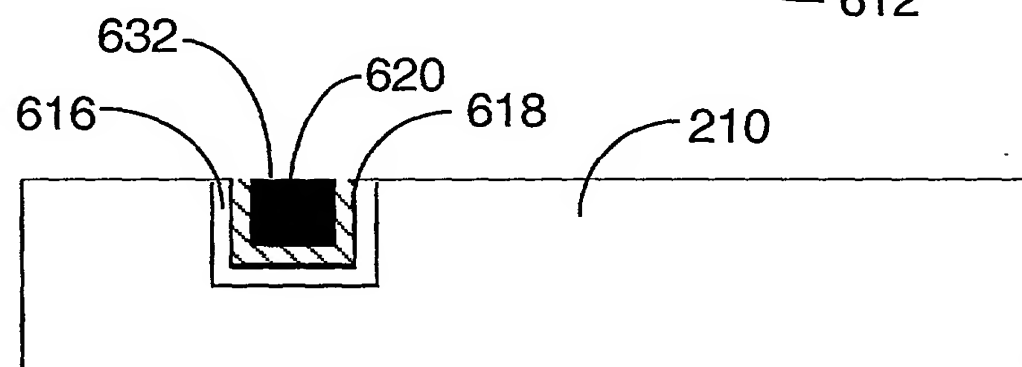
(b)



(c)



(d)



(e)

Figure 5

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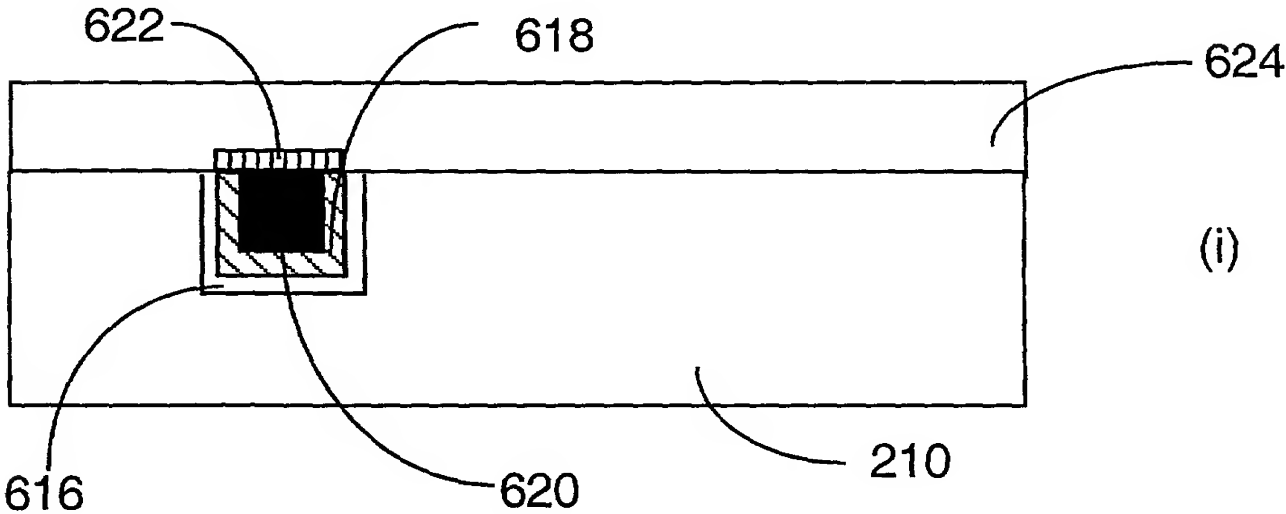
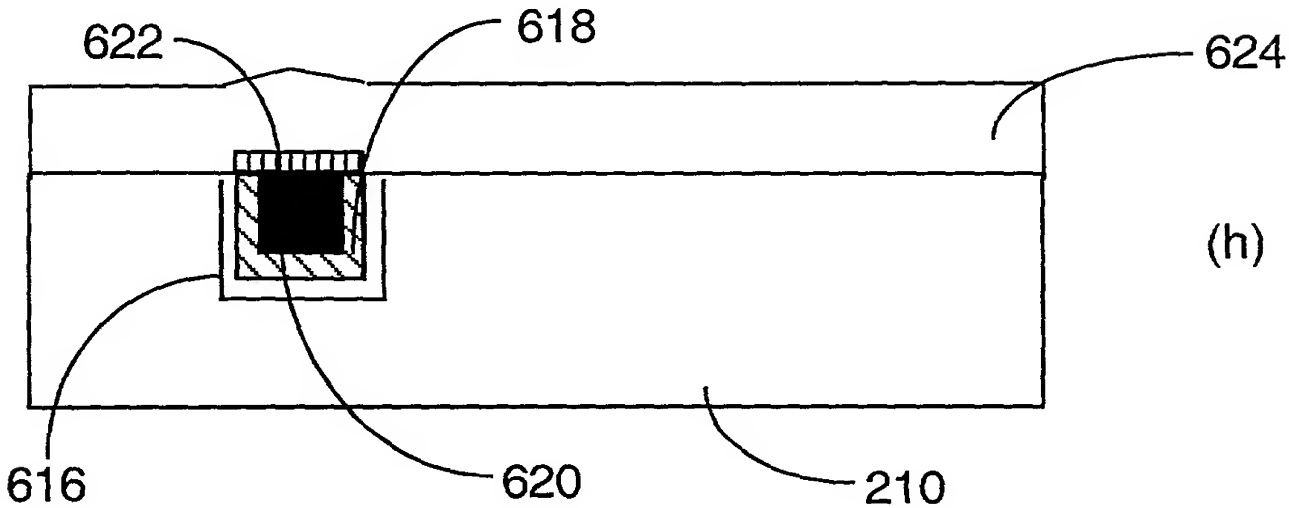
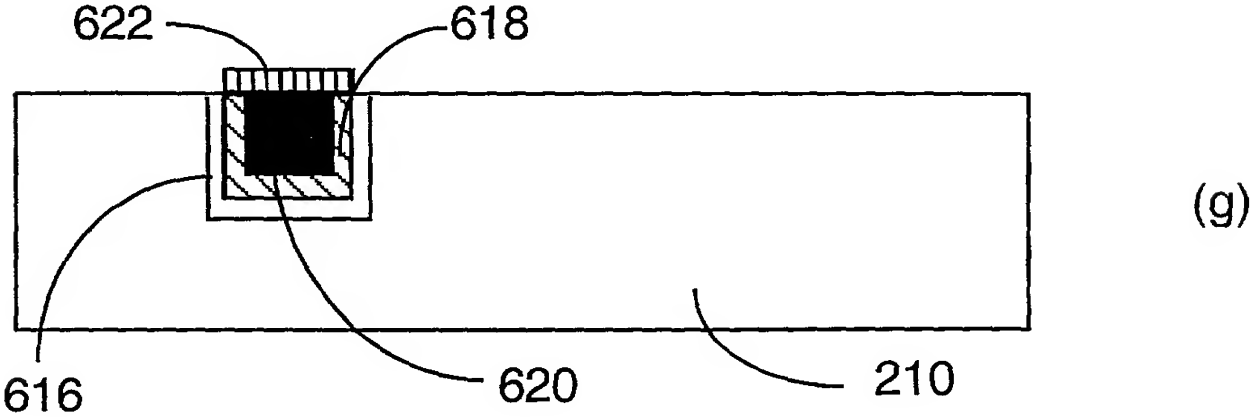
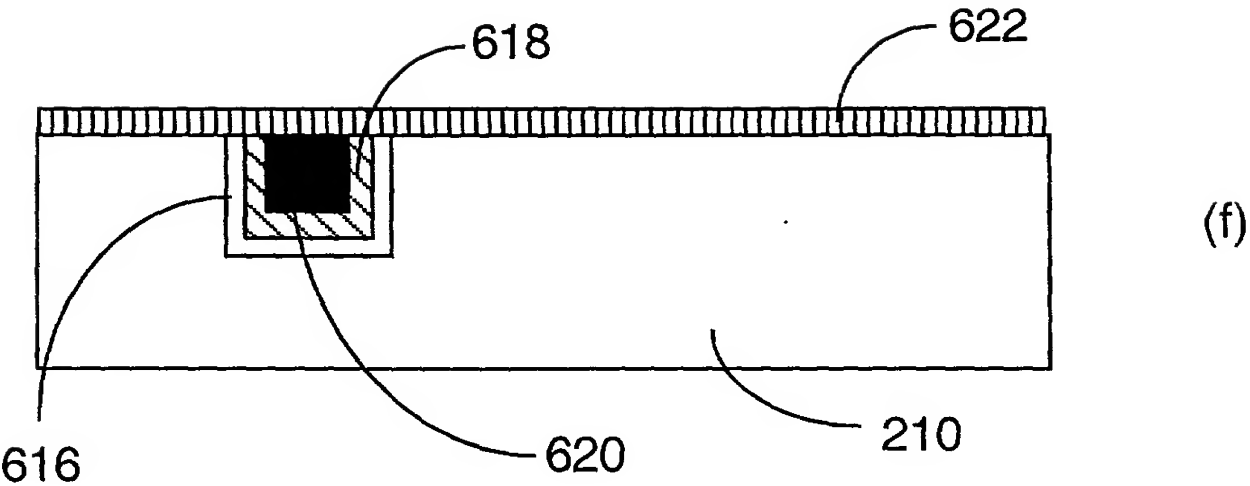
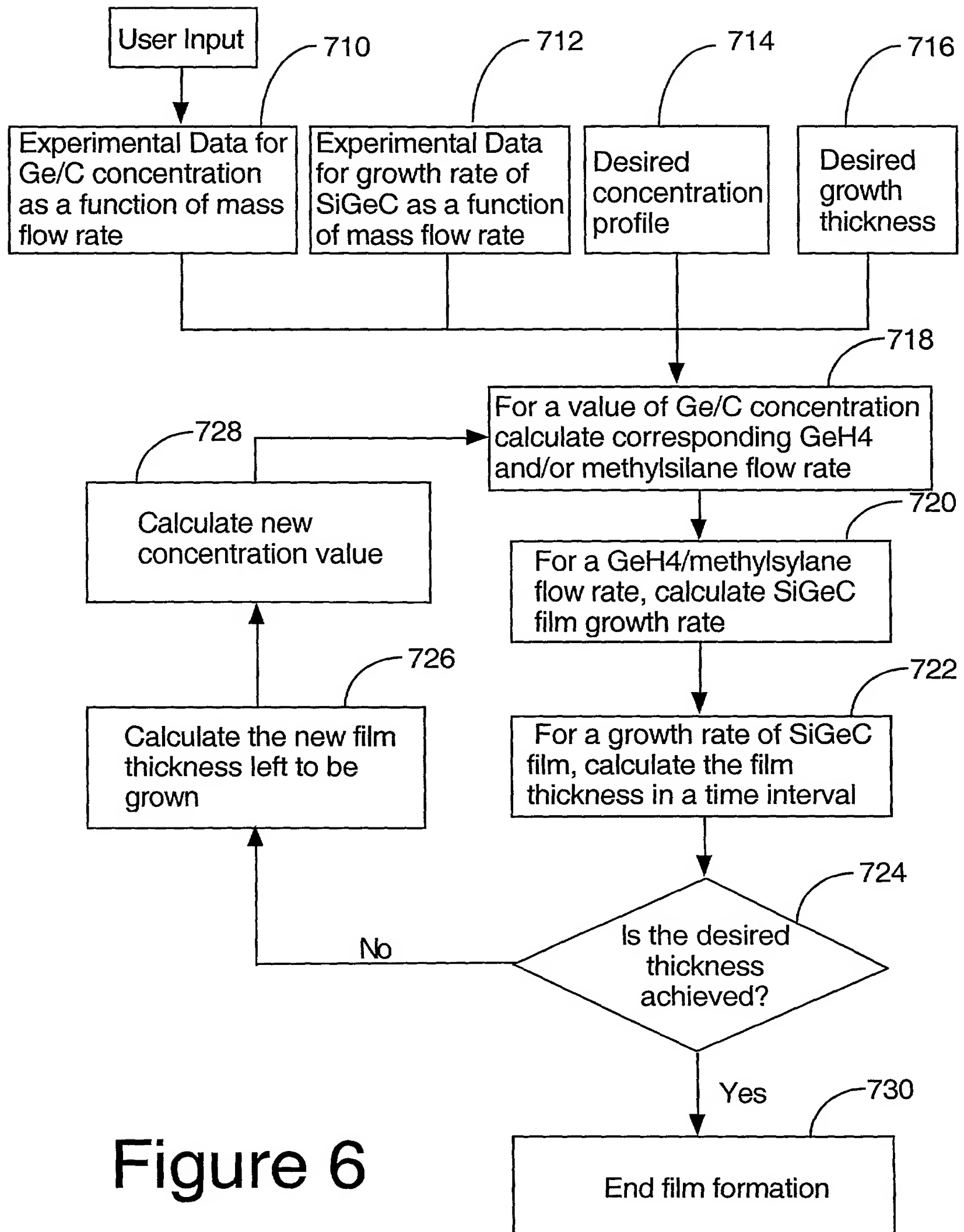


Figure 5

**Figure 6**

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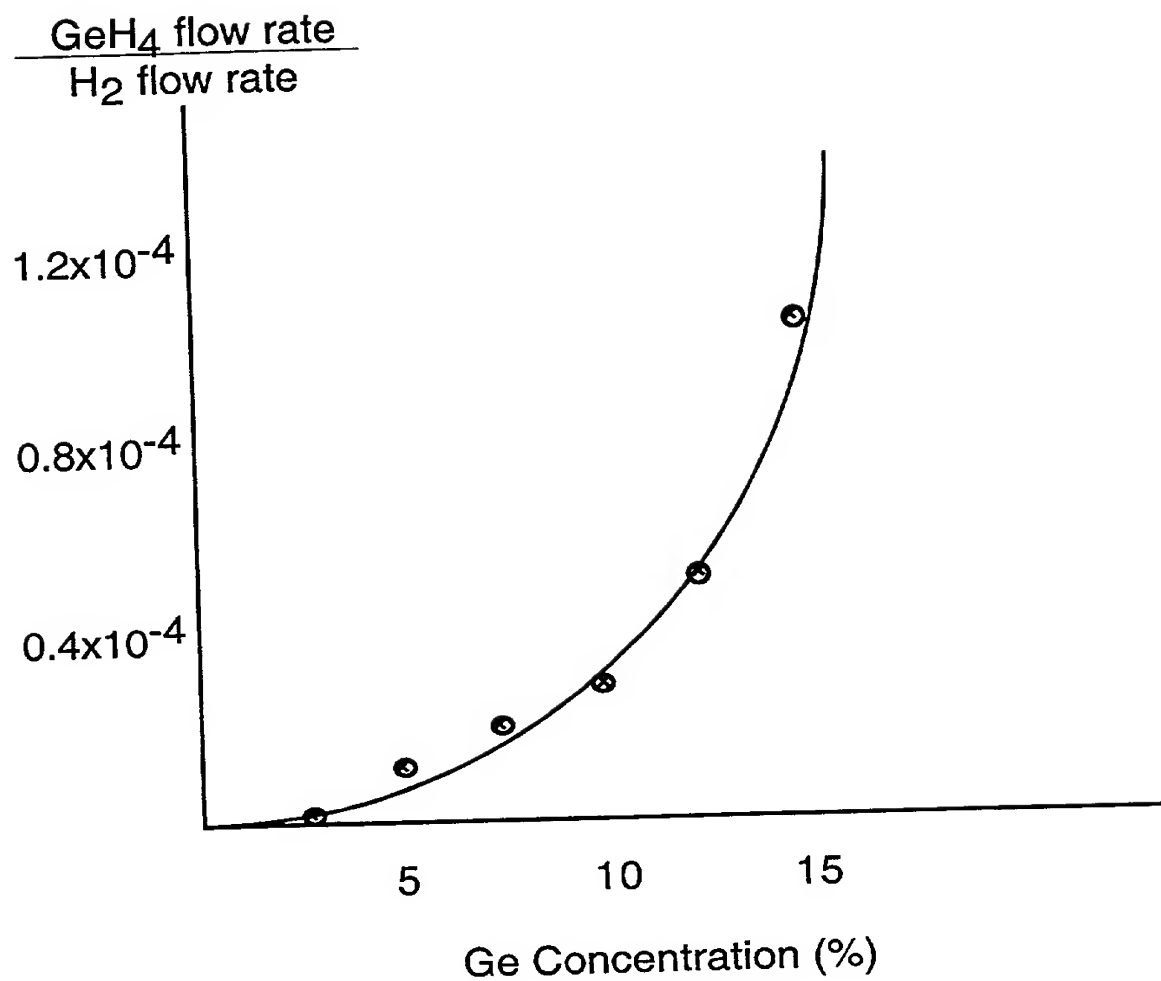


Figure 7A

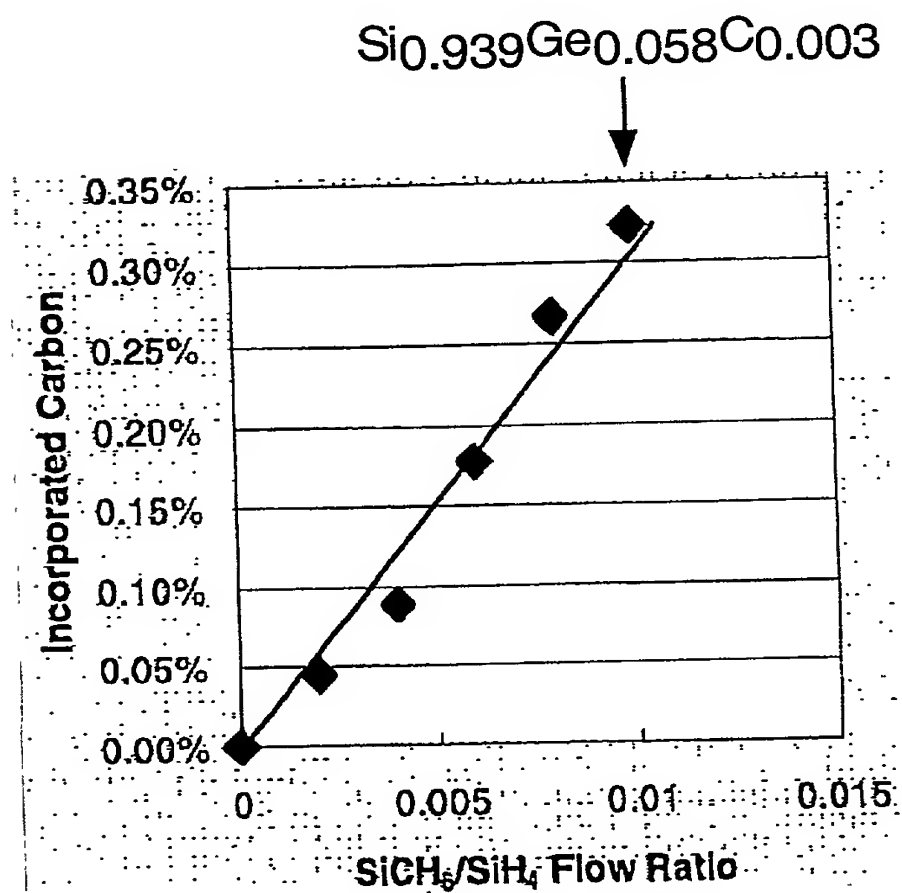


Figure 7B

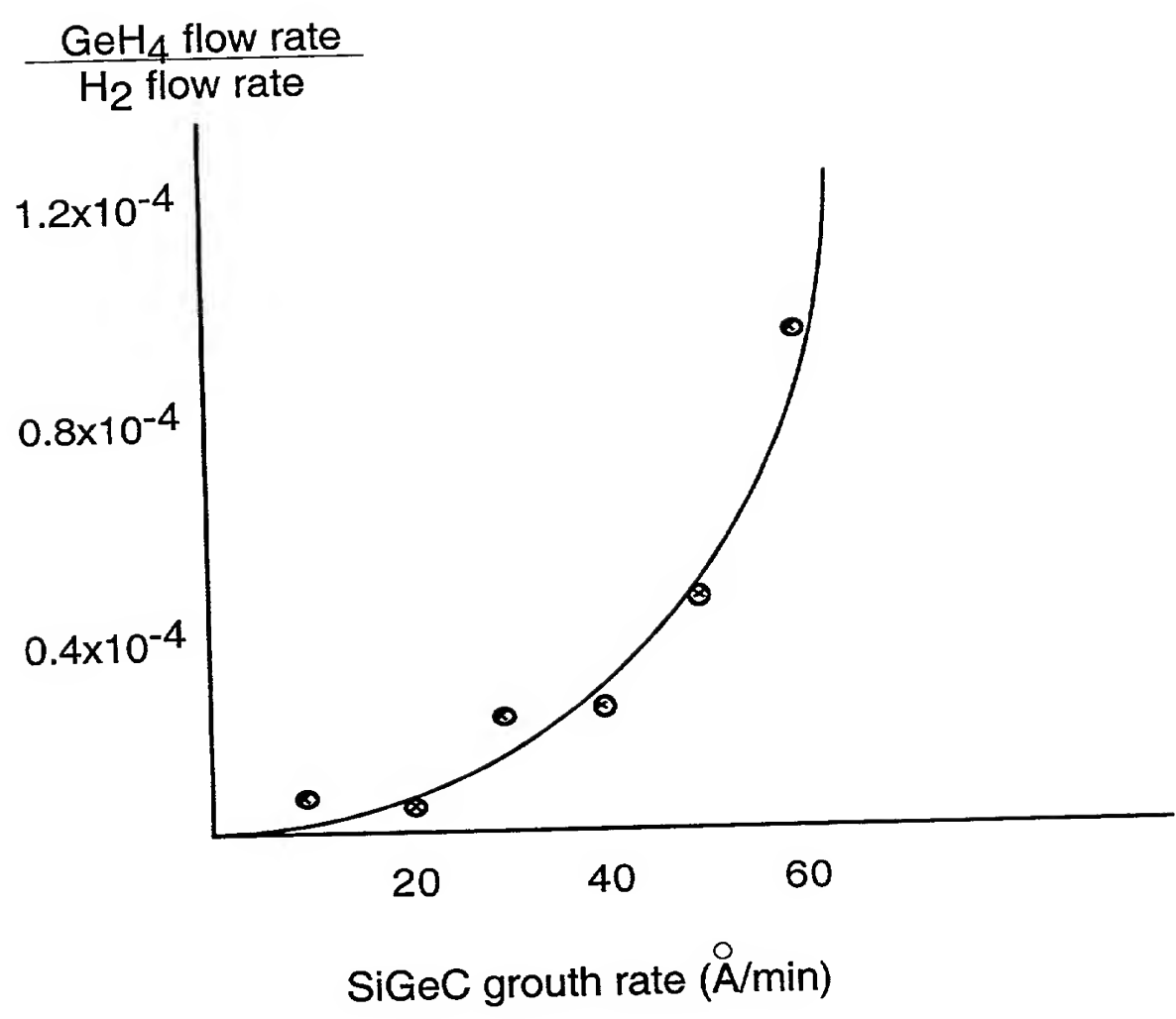
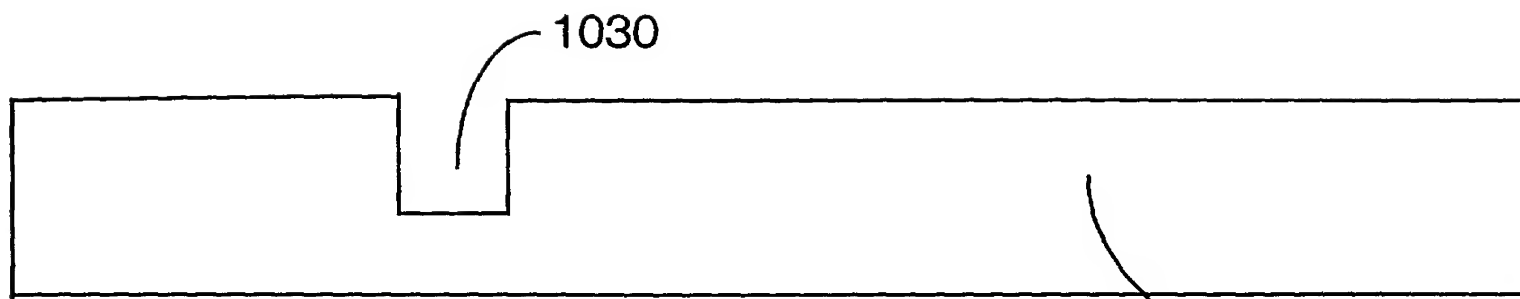
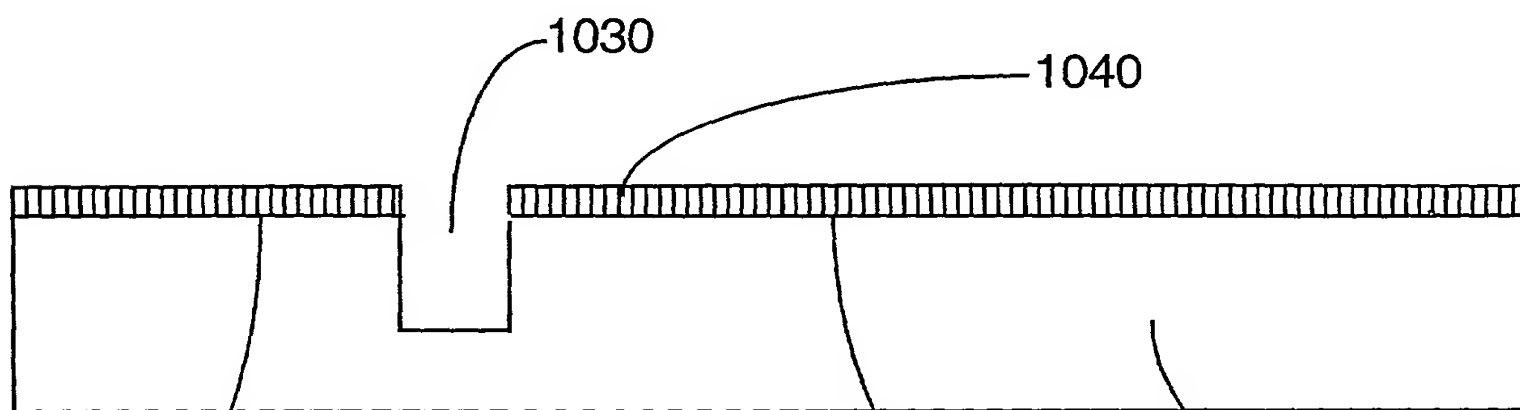


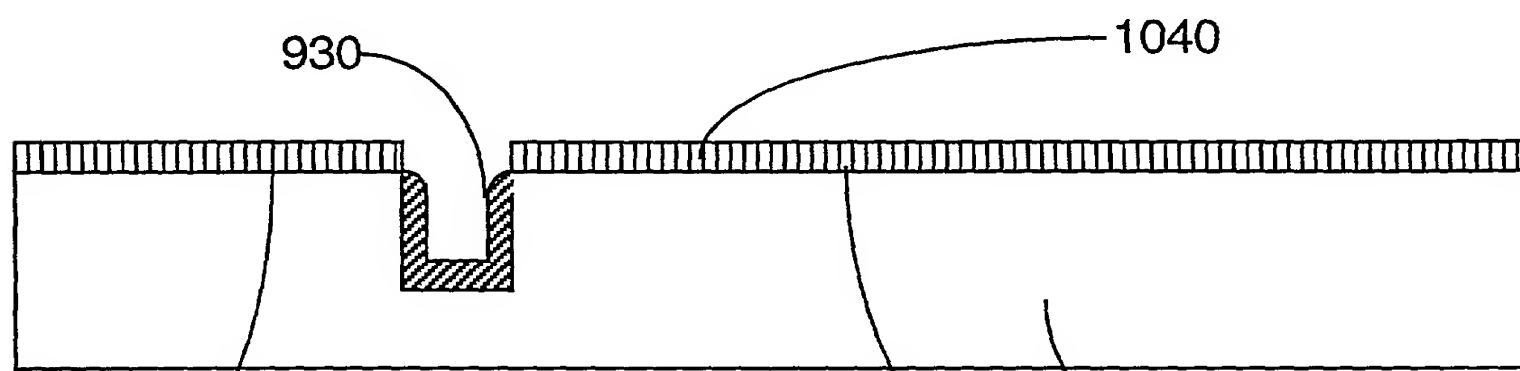
Figure 8



(a)



(b)



(c)

Figure 9

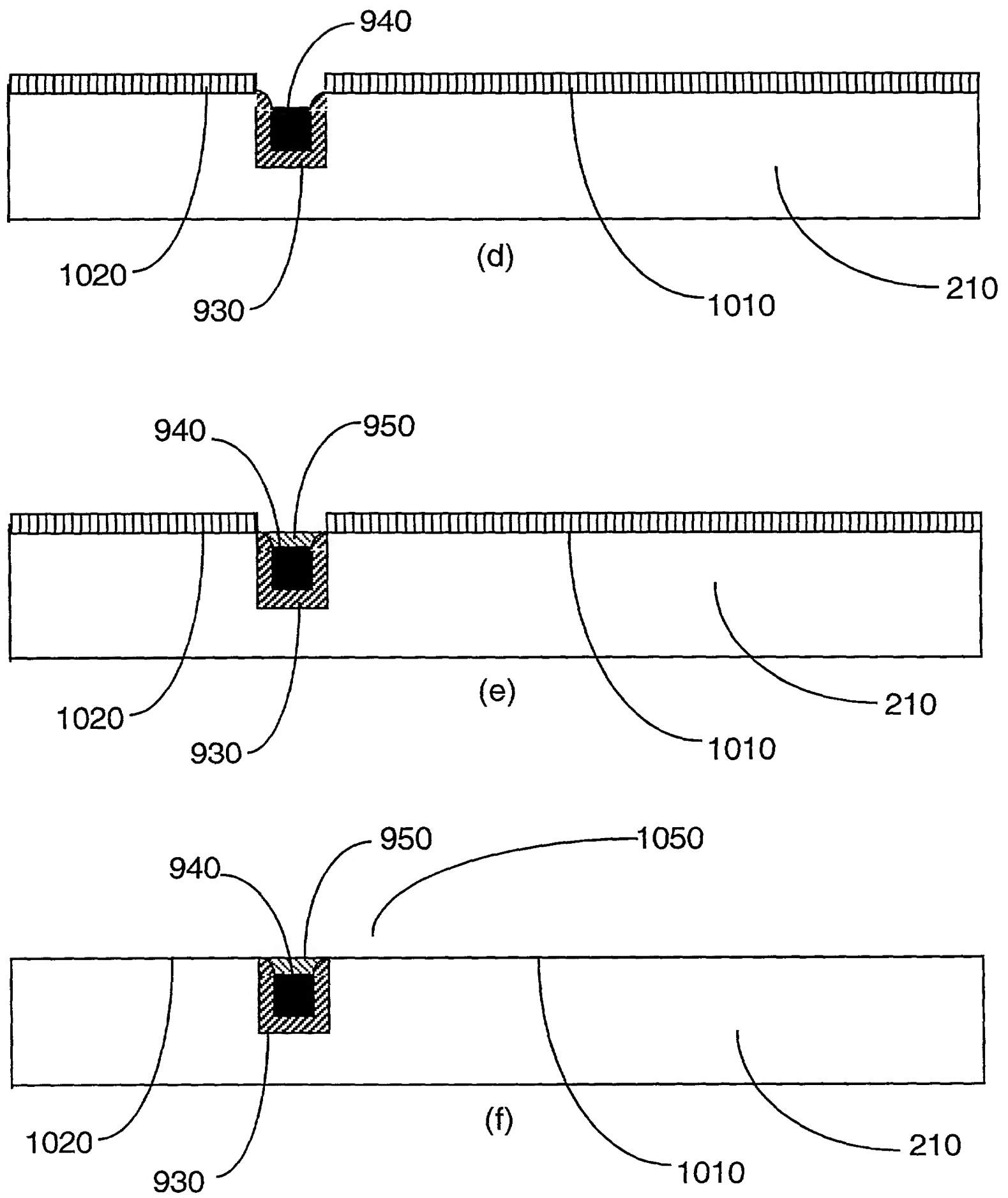


Figure 9

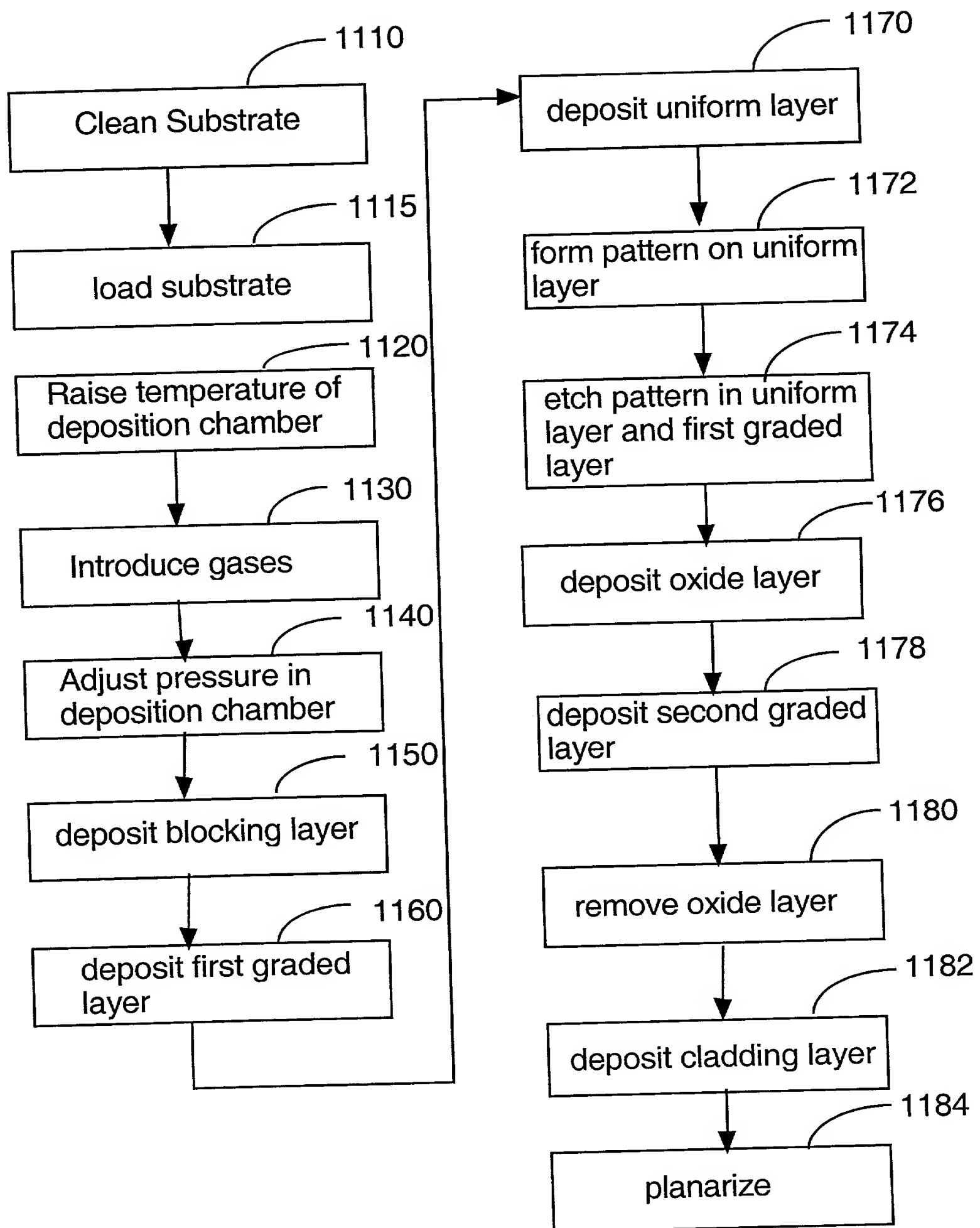


Figure 10

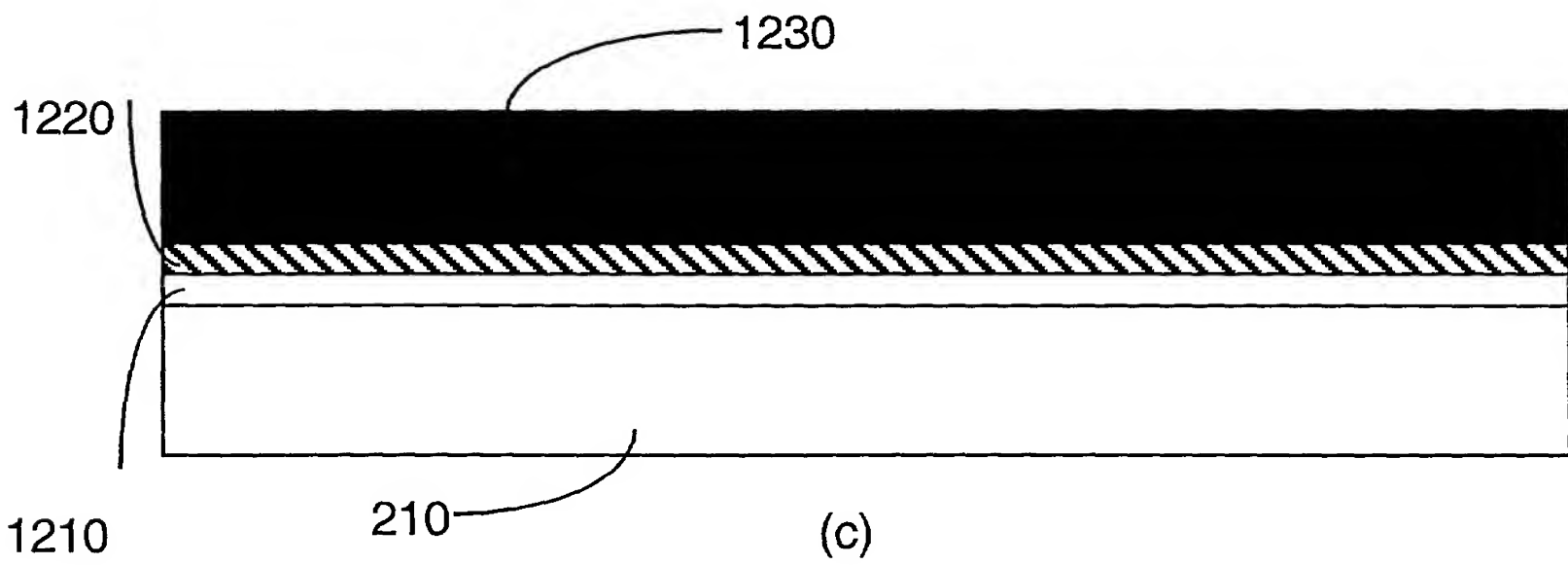
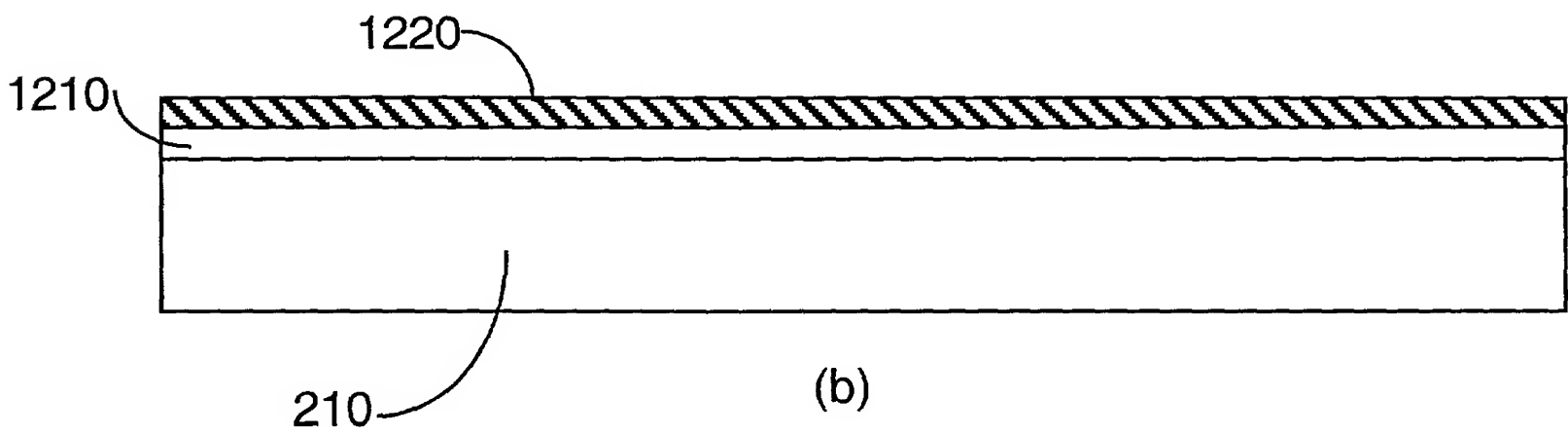
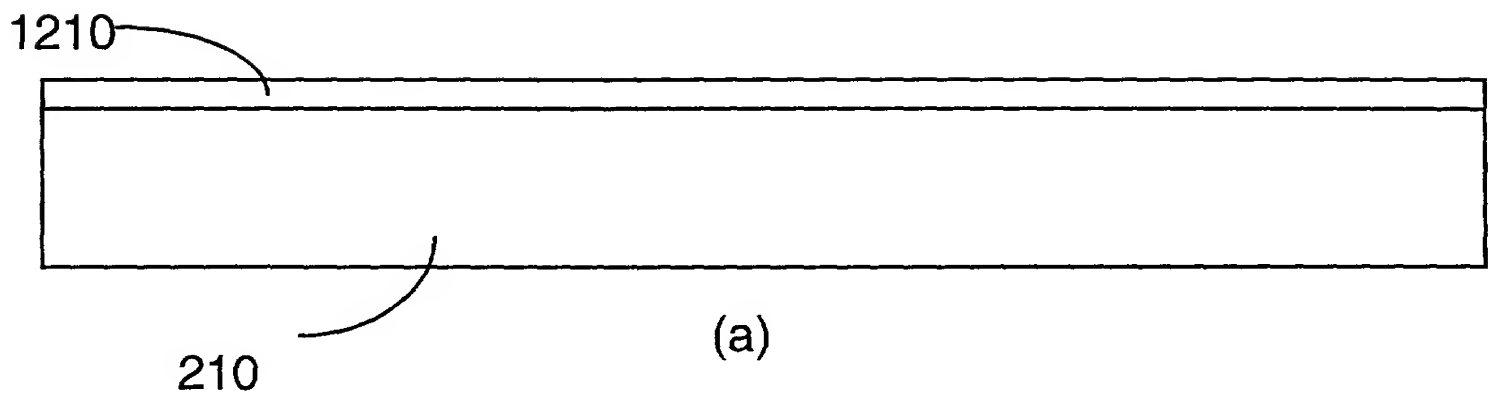


Figure 11

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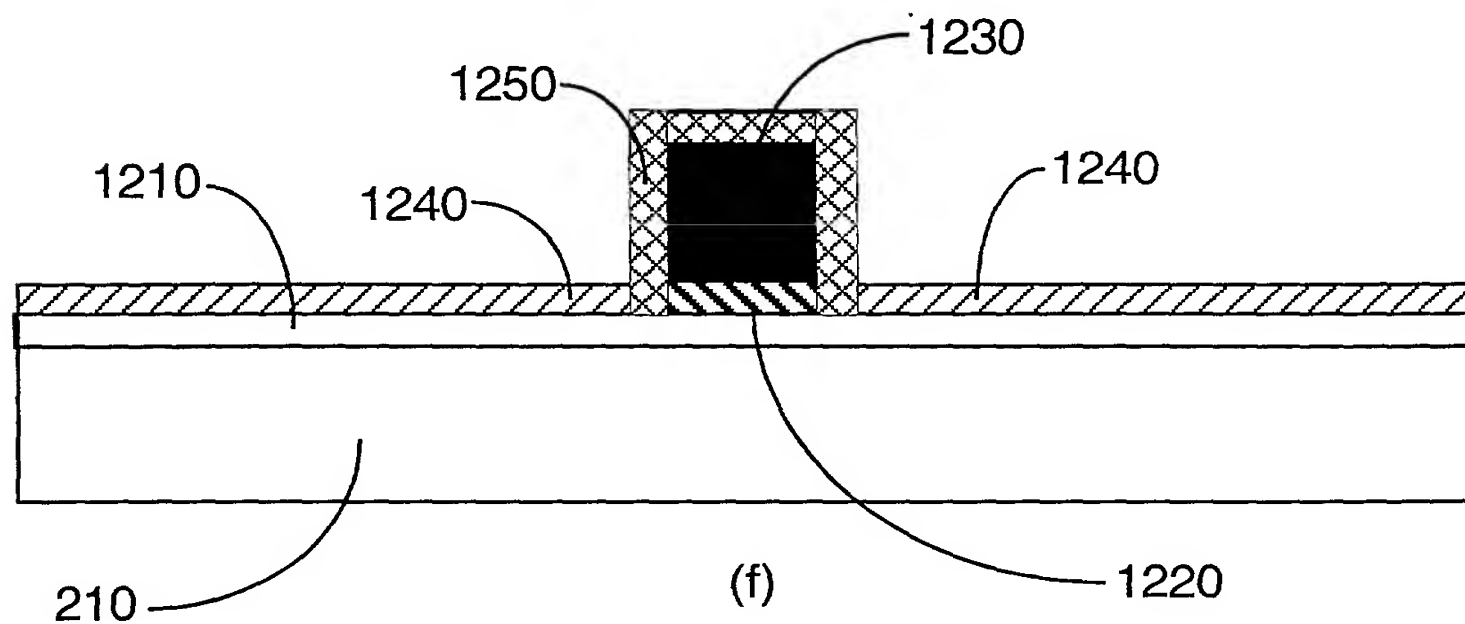
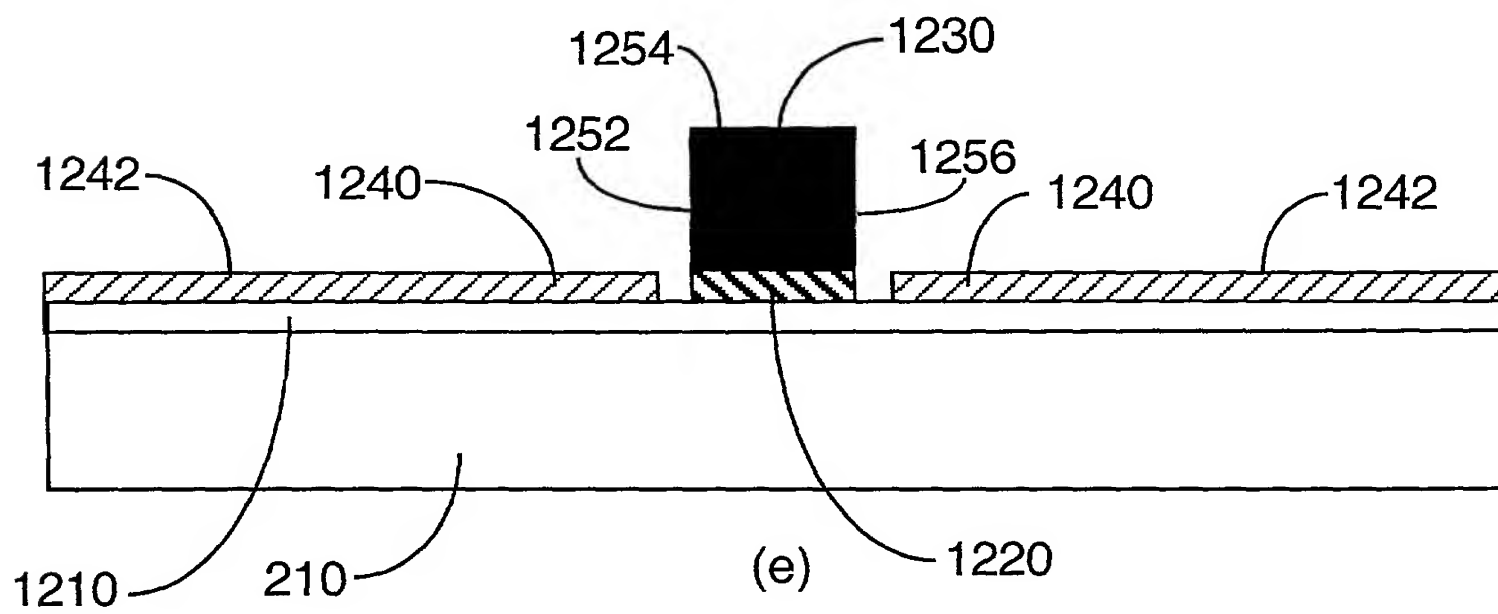
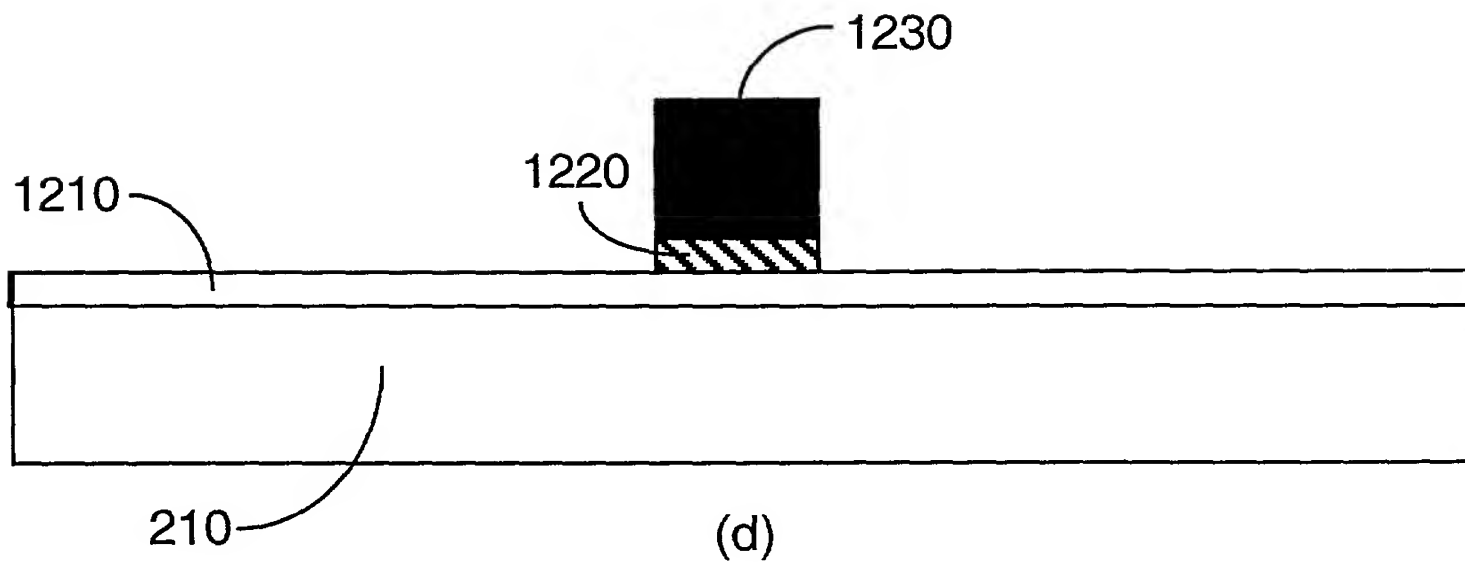


Figure 11

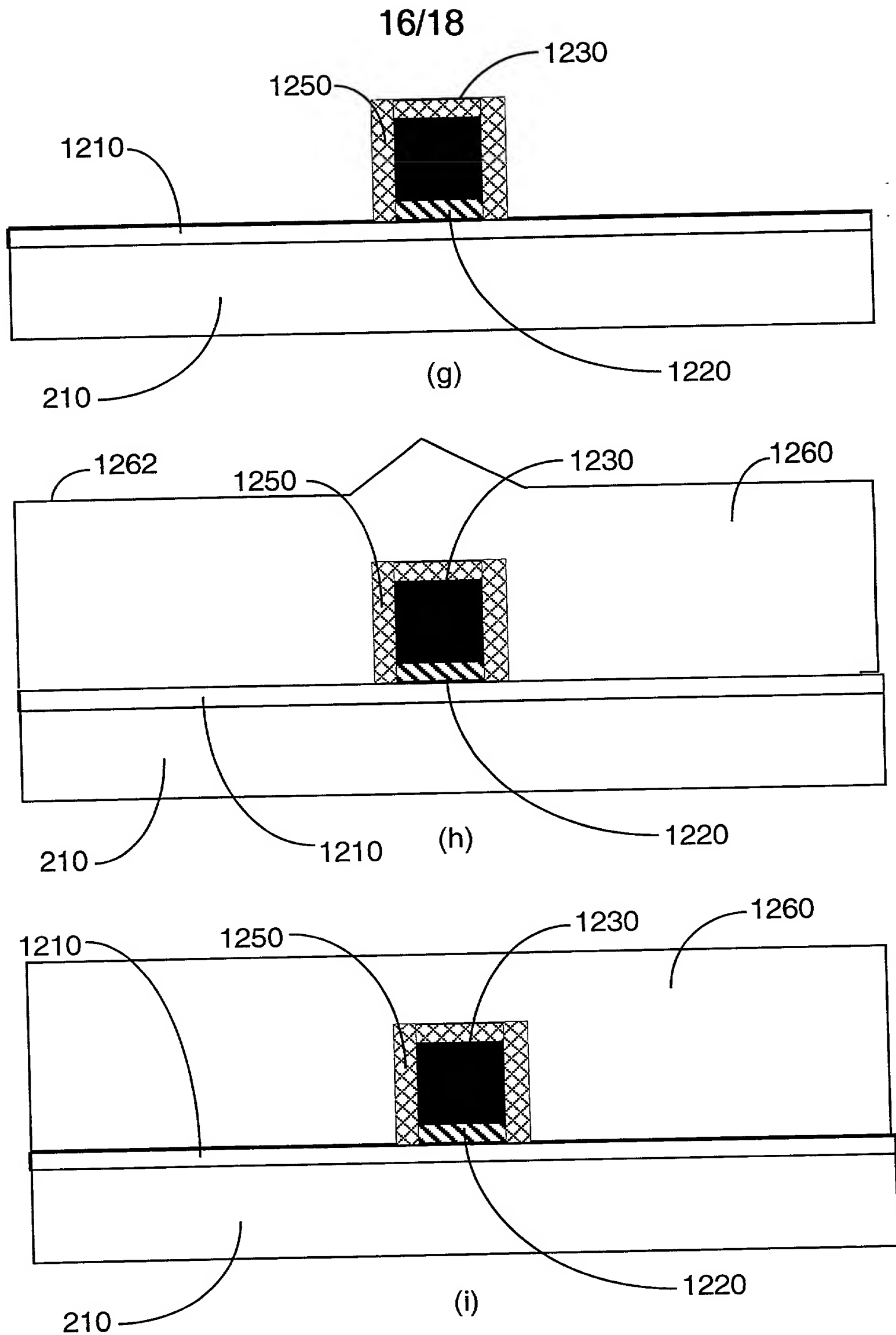


Figure 11

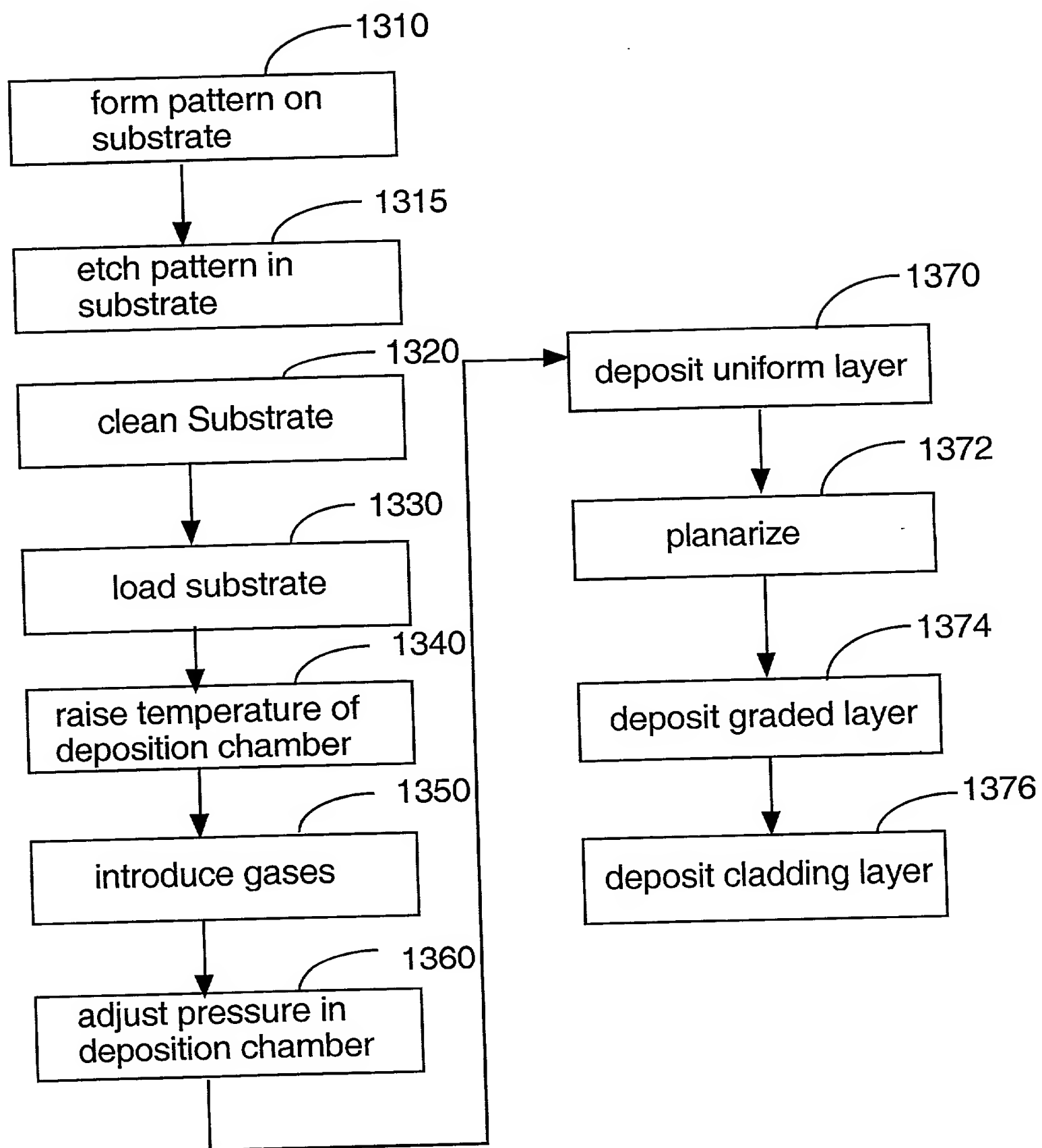


Figure 12

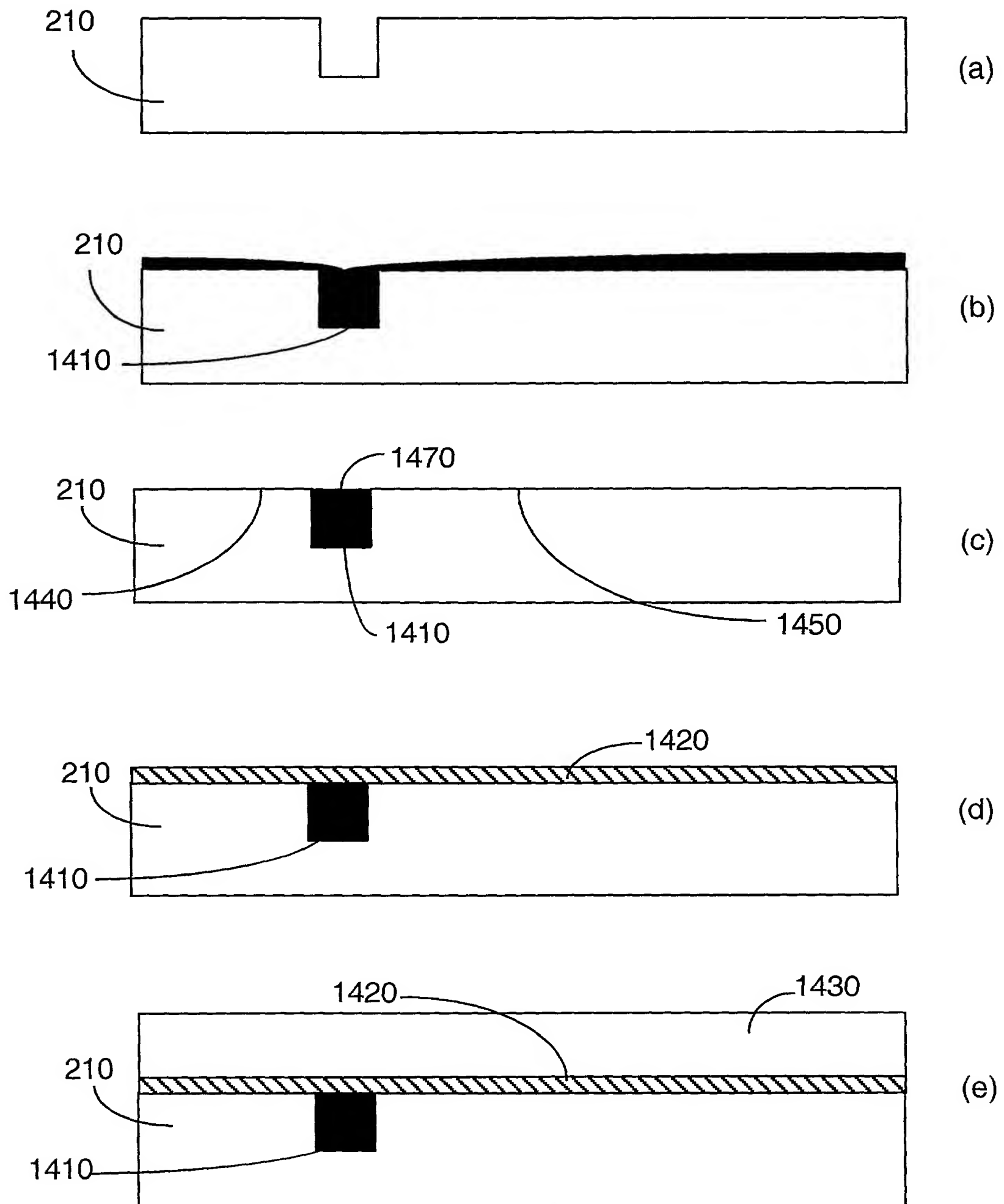


Figure 13